

ICS 71.040.40
CCS G 04



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 29557-2013

**Surface chemical analysis -- Depth Profiling -- Measurement of
sputtered depth**

表面化学分析 深度剖析 溅射深度测量

(English Translation)

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What this standard covers

This standard specifies: sputter sputter depth profiling measured depth criteria. This standard applies to divest some combination of ion bombardment of solid samples surface chemical analysis techniques, usually sputter depth of up to a few microns.

Document data

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